

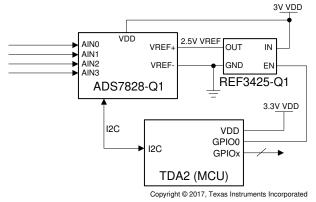
REF34-Q1 Low-Drift, Low-Power, Small-Footprint Series **Voltage References**

1 Features

- AEC-Q100 qualified with the following results:
 - Device temperature grade 1: -40°C to +125°C ambient operating temperature
 - Device HBM ESD classification level 2
 - Device CDM ESD classification level C6
- Initial accuracy: ±0.05% (maximum)
- Temperature coefficient: 6 ppm/°C (maximum)
- Operating temperature range: -40°C to +125°C
- Output voltage options: 2.5V, 3.0V, 3.3V, 4.096V, 5.0V
- Output current: ±10 mA
- Low guiescent current: 95 µA (maximum)
- Low shutdown mode current: 3 µA (maximum)
- Wide input voltage: 12 V
- Output 1/f noise (0.1 Hz to 10 Hz): $3.8 \mu V_{PP}/V$
- Excellent long-term stability 25 ppm/1000 hrs
- Available in 6-pin and 5-Pin SOT-23 package and 8-pin MSOP package

2 Applications

- Body control modules
- On board chargers
- **Traction inverters**
- Battery management systems
- Advanced driver assistance systems



Simplified Schematic

3 Description

The REF34-Q1 devices are low-temperature-drift (6 ppm/°C), low-power, high-precision CMOS voltage references. The devices have ±0.05% initial accuracy and low operating current with power consumption less than 95 µA. These devices also offer very low output noise of 3.8 µV_{PP}/V, which enable the devices to maintain high signal integrity with high-resolution data converters and noise critical systems.

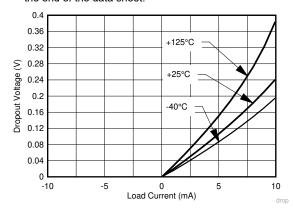
Stability and system reliability are further improved by the low output-voltage hysteresis of these devices and low long-term output voltage drift. Furthermore, the small size and low operating current of the devices (95 µA) make them an excellent choise for batterypowered applications. The REF34-Q1 features an enable pin that can set the device into shutdown where it consumes a low stand by current (3 µA) to help with overall system power during standby.

The REF34-Q1 family is specified for the wide temperature range of -40°C to +125°C. Contact the TI sales representative for additional voltage options.

Device Information (1)

201100 1111011110111						
PART NUMBER	PACKAGE	BODY SIZE (NOM)				
REF34xx-Q1	SOT-23 (6)	2.90 mm × 1.60 mm				
REF34xxS-Q1	SOT-23 (5)	2.90 mm × 1.60 mm				
REF34xx-Q1	VSSOP (8)	4.00 mm × 4.00 mm				

For all available packages, see the orderable addendum at the end of the data sheet.



Dropout vs Current Load Over Temperature



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4 Revision History			

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision B (August 2020) to Revision C (October 2020)		
Added information for REF34-Q1 DGK Package	3	
Added information for REF34xx-Q1 DGK package pin functions	3	
Changes from Revision A (September 2018) to Revision B (August 2020)	Page	
Added information for REF34xxS-Q1	3	
Added information for REF34xxS-Q1	3	
	_	
Changes from Revision * (July 2018) to Revision A (September 2018)	Page	



5 Device Comparison Table

PRODU	V _{OUT}	
REF3425-Q1	REF3425S-Q1	2.5 V
REF3430-Q1	REF3430S-Q1	3.0 V
REF3433-Q1	REF3433S-Q1	3.3 V
REF3440-Q1	REF3440S-Q1	4.096 V
REF3450-Q1	REF3450S-Q1	5.0 V

⁽¹⁾ For full orderable part number please refer to Section 15.

6 Pin Configuration and Functions

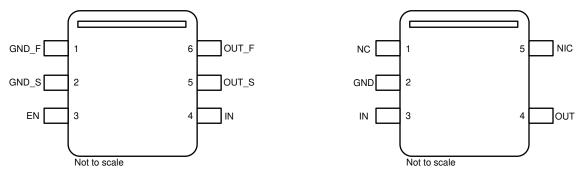


Figure 6-1. DBV Package 6-Pin SOT-23 (Top View) Figure 6-2. DBV Package 5-Pin SOT-23 (Top View)

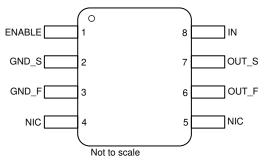


Figure 6-3. DGK Package 8-Pin VSSOP (Top View)

6.1 Pin Functions

	PIN				
NAME	REF34xx-Q1 (DBV)	REF34xxS-Q1 (DBV)	REF34xx- Q1 (DGK)	TYPE	DESCRIPTION
GND_F	1	-	3	Ground	Ground force connection
GND_S	2	-	2	Ground	Ground sense connection
GND	-	2	-	Ground	Ground connection
ENABLE	3	-	1	Input	Enable connection. Enables or disables the device.
IN	4	3	8	Power	Input supply voltage connection
OUT_S	5	-	7	Output	Reference voltage output sense connection
OUT_F	6	-	6	Output	Reference voltage output force connection
OUT	-	4	-	Output	Reference voltage output connection
NC	-	1	-	-	Test pin, connect from 0V to 18V
NIC	-	5	4,5	-	No internal connection



7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
Input voltogo	IN	-0.3	13	V
Input voltage	EN	-0.3	IN + 0.3	V
Output voltage V _{OUT}		-0.3	5.5	V
Output short circuit current		20	mA	
Operating temperature range, T _A	-55	150	°C	
Storage temperature range, T _{stg}	-65	170	°C	

⁽¹⁾ Stresses above these ratings may cause permanent damage. Exposure to absolute maximum conditions for extended periods may degrade device reliability. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those specified is not implied. These are stress ratings only and functional operation of the device at these or any other conditions beyond those specified in the Electrical Characteristics Table is not implied.

7.2 ESD Ratings

			VALUE	UNIT
		Human-body model (HBM), per AEC Q100-002 ⁽¹⁾	±2500	
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per AEC Q100-011	±1500	V

⁽¹⁾ AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
IN	Input Voltage	V _{OUT} + V _{DO} ⁽¹⁾		12	V
EN	Enable Voltage	0		IN	V
IL	Output Current	-10		10	mA
T _A	Operating Temperature	-40	25	125	°C

⁽¹⁾ V_{DO} = Dropout voltage

7.4 Thermal Information

		REF34-Q1			
	THERMAL METRIC ⁽¹⁾	DBV	DGK	UNIT	
		5 PINS	6 PINS	8 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	122.6	122.6	174.1	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	80.2	80.2	61.3	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	42	42	95.5	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	23.2	23.2	8.5	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	41.9	41.9	93.9	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

Product Folder Links: REF34-Q1



7.5 Electrical Characteristics

At V_{IN} = V_{OUT} + V_{DO} , C_{OUT} = 10 μ F, C_{IN} = 0.1 μ F, I_L = 0 mA, minimum and maximum specifications at T_A = -40° C to 125°C; Typical specifications at T_A = 25°C unless otherwise noted

	PARAMETER	TEST CO	ONDITION	MIN	TYP	MAX	UNIT
ACCURAC	Y AND DRIFT						
	Output voltage accuracy	T _A = 25°C		-0.05		0.05	%
	Output voltage temperature coefficient				2.5	6	ppm/°C
I INF & I O	AD REGULATION						
	REGOLATION	$V_{IN} = V_{OUT} + V_{DO}$ (2) to 1	2 V		2		
$\Delta V_{O}/\Delta V_{IN}$	Line Regulation	$V_{IN} = V_{OUT} + V_{DO}$ (2) to 1				15	ppm/V
		$I_L = 0 \text{ mA to } 10\text{mA}, V_{IN}$	Sourcing		20		
		$= V_{OUT} + V_{DO}^{(3)}$	Sourcing			30	
			Sinking, REF3425-Q1		40		
			Sinking, REF3430-Q1		43		
			Sinking, REF3433-Q1		48		
			Sinking, REF3440-Q1		60		
$\Delta V_O/\Delta I_L$	Load Regulation	$I_L = 0$ mA to -10 mA, V_{IN}	Sinking, REF3450-Q1		70		ppm/mA
		$= V_{OUT} + V_{DO}^{(3)}$	Sinking, REF3425-Q1			70	
			Sinking, REF3430-Q1			75	
			Sinking, REF3433-Q1			84	
			Sinking, REF3440-Q1			98	
			Sinking, REF3450-Q1			140	
NOISE			<u> </u>				
		0.1Hz ≤ f ≤ 10Hz			5		
e _{np-p}	Low frequency noise (4)	0.1Hz ≤ f ≤ 10Hz (REF34 Q1)	0.1Hz ≤ f ≤ 10Hz (REF3440–Q1 and REF3450–		3.8		μV p–p/V
e _n	Integrated wide band noise	10Hz ≤ f ≤ 10kHz			24		μVrms
_	Output voltage noise	f = 1kHz			0.25		ppm/√Hz
e _n	density	f = 1kHz (REF3440-Q1	and REF3450-Q1)		0.2		
LONG TER	RM STABILITY AND HYS	TERESIS	-			'	
	Long-term stability (5)	DBV Package	0 to 1000h at 35°C		25		
	Long-term stability	рву Раскаде	1000h to 2000h at 35°C		10		ppm
	Long-term stability (5)	DGK Package	0 to 1000h at 35°C		17		
		DBV Package	25°C, –40°C,125°C, 25°C Cycle 1		30		
	Output voltage thermal	DDV I ackage	25°C, -40°C,125°C, 25°C Cycle 2		10		ppm
	hysteresis ⁽⁶⁾	DGK Package	25°C, –40°C,125°C, 25°C Cycle 1		20		ррш
		DON Fackage	25°C, -40°C,125°C, 25°C Cycle 2		10		
TURN-ON	TIME						
t _{ON}	Turn-on time	0.1% of output voltage so REF3425–Q1	0.1% of output voltage settling, C _L = 10 μF, REF3425–Q1		2.5		ms
CAPACITI	VE LOAD						
C_{L}	Stable output capacitor range			0.1		10	μF



At V_{IN} = V_{OUT} + V_{DO} , C_{OUT} = 10 μ F, C_{IN} = 0.1 μ F, I_L = 0 mA, minimum and maximum specifications at T_A = -40° C to 125°C; Typical specifications at T_A = 25°C unless otherwise noted

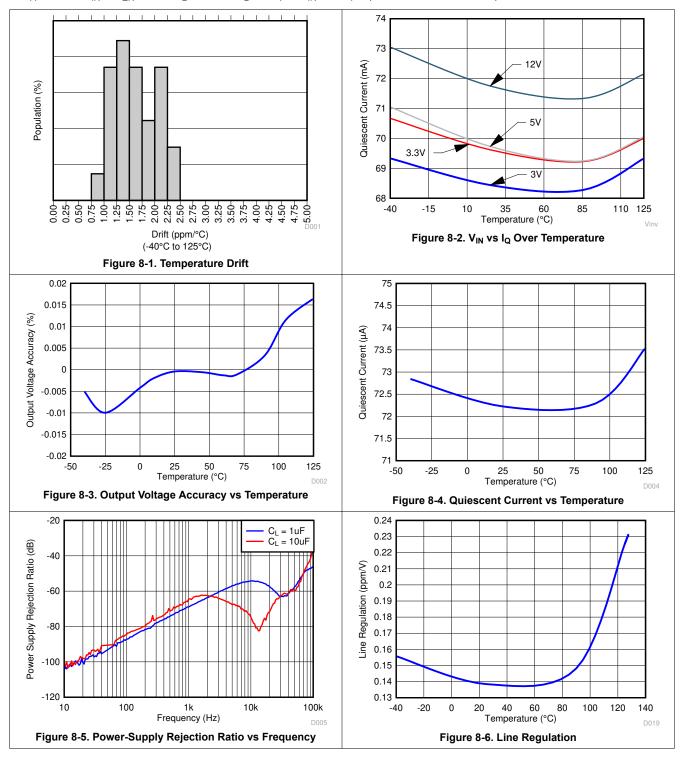
PARAMETER		TEST CONDITION	MIN	TYP	MAX	UNIT
OUTPUT	VOLTAGE					
		REF3425Q1		2.5		
		REF3430Q1		3.0		
V_{OUT}	Output voltage	REF3433Q1		3.3		V
		REF3440Q1		4.096		
		REF3450Q1		5.0		
POWER	SUPPLY					
V _{IN}	Input voltage		V _{OUT} + V		12	V
V IIN	mpat voltago		DO			•
IL	Output current capacity	$V_{IN} = V_{OUT} + V_{DO}$ to 12 V	-10		10	mA
1-	Quiescent current	Active mode		72	95	
IQ	Quiescent current	Shutdown mode (7)		2.5	3	μA
		I _L = 0 mA		50		
V_{DO}	Dropout voltage	I _L = 0 mA			100	mV
		I _L = 10 mA			500	
\/	ENABLE pin voltage ⁽⁷⁾	Voltage reference in active mode (EN = 1)	1.6			V
V_{EN}	ENABLE pili voltage (*)	Voltage reference in shutdown mode (EN = 0)			0.5	
I _{EN}	ENABLE pin leakage current ⁽⁷⁾	V _{EN} = V _{IN} = 12V 1 2		2	μA	
I _{SC}	Short circuit current	V _{OUT} = 0 V at T _A = 25°C		18	22	mA

- (1) Temperature drift is specified according to the box method. See Low Temperature Drift section for more details.
- (2) V_{DO} for line regulation test is 50 mV.
- (3) V_{DO} for load regulation test is 500 mV.
- (4) The peak-to-peak noise measurement is explained in more detail in section Noise Performance.
- (5) Long-term stability measurement procedure is explained in more detail in section Long-Term Stability.
- (6) Thermal hysteresis measurement procedure is explained in more detail in section Thermal Hysteresis.
- (7) Not applicable for REF34S device (DBV 5 pin package)



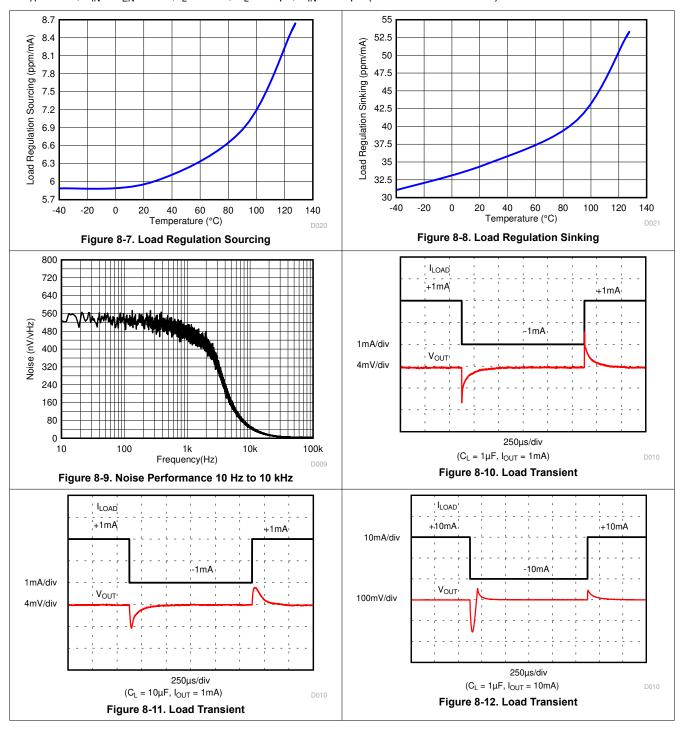
8 Typical Characteristics

at T_A = 25°C, V_{IN} = V_{EN} = 12 V, I_L = 0 mA, C_L = 10 μ F, C_{IN} = 0.1 μ F (unless otherwise noted)





at T_A = 25°C, V_{IN} = V_{EN} = 12 V, I_L = 0 mA, C_L = 10 μ F, C_{IN} = 0.1 μ F (unless otherwise noted)

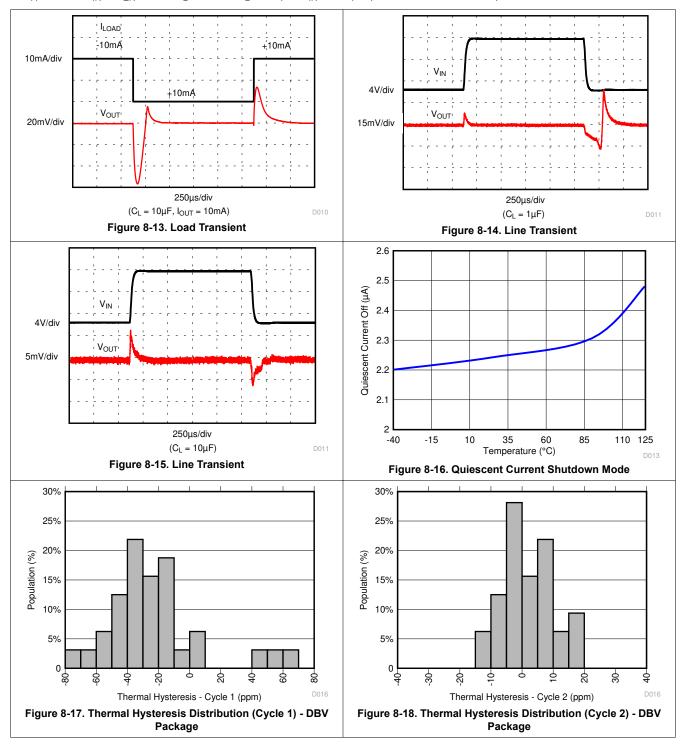


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at T_A = 25°C, V_{IN} = V_{EN} = 12 V, I_L = 0 mA, C_L = 10 μ F, C_{IN} = 0.1 μ F (unless otherwise noted)





at T_A = 25°C, V_{IN} = V_{EN} = 12 V, I_L = 0 mA, C_L = 10 μ F, C_{IN} = 0.1 μ F (unless otherwise noted)

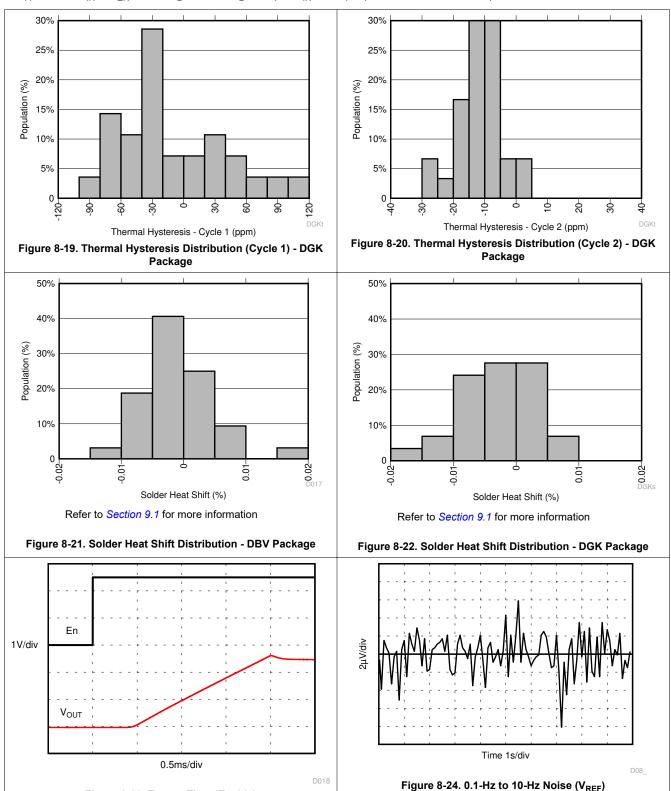


Figure 8-23. Turnon Time (Enable)



at T_A = 25°C, V_{IN} = V_{EN} = 12 V, I_L = 0 mA, C_L = 10 μ F, C_{IN} = 0.1 μ F (unless otherwise noted)

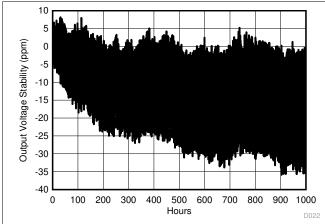


Figure 8-25. Long Term Stability - 1000 hours (V_{REF}) - DBV Package

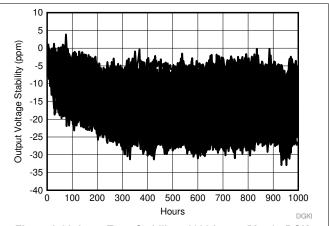


Figure 8-26. Long Term Stability - 1000 hours (V_{REF}) - DGK Package



9 Parameter Measurement Information

9.1 Solder Heat Shift

The materials used in the manufacture of the REF34-Q1 have differing coefficients of thermal expansion, resulting in stress on the device die when the part is heated. Mechanical and thermal stress on the device die can cause the output voltages to shift, degrading the initial accuracy specifications of the product. Reflow soldering is a common cause of this error.

In order to illustrate this effect, a total of 32 devices were soldered on four printed circuit boards [16 devices on each printed circuit board (PCB)] using lead-free solder paste and the paste manufacturer suggested reflow profile. The reflow profile is as shown in Figure 9-1. The printed circuit board is comprised of FR4 material. The board thickness is 1.65 mm and the area is 114 mm × 152 mm. All measurements were taken after baking at 150°C.

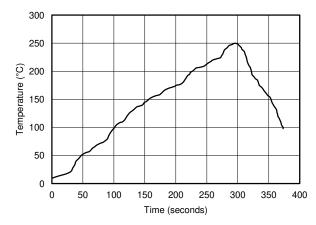
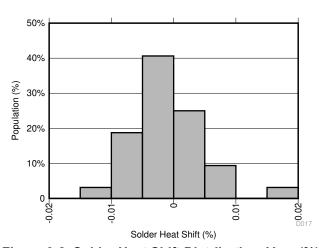
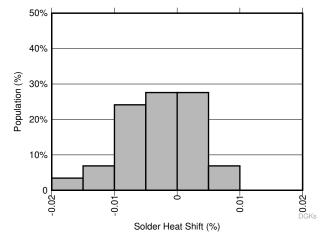


Figure 9-1. Reflow Profile

The reference output voltage is measured before and after the reflow process; the typical shift is displayed in Figure 9-2. Although all tested units exhibit very low shifts (< 0.01%), higher shifts are also possible depending on the size, thickness, and material of the printed circuit board. An important note is that the histograms display the typical shift for exposure to a single reflow profile. Exposure to multiple reflows, as is common on PCBs with surface-mount components on both sides, causes additional shifts in the output bias voltage. If the PCB is exposed to multiple reflows, the device must be soldered in the second pass to minimize its exposure to thermal stress.





- DBV Package

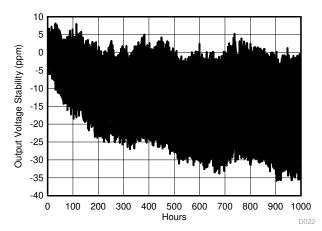
Figure 9-2. Solder Heat Shift Distribution, V_{REF} (%) Figure 9-3. Solder Heat Shift Distribution, V_{REF} (%) - DGK Package

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9.2 Long-Term Stability

One of the key parameters of the REF34-Q1 references is long-term stability. Typical characteristic expressed as: curves shows the typical drift value for the REF34-Q1 is 25 ppm from 0 to 1000 hours. This parameter is characterized by measuring 32 units at regular intervals for a period of 1000 hours. It is important to understand that long-term stability is not ensured by design and that the output from the device may shift beyond the typical 25 ppm specification at any time. For systems that require highly stable output voltages over long periods of time, the designer should consider burning in the devices prior to use to minimize the amount of output drift exhibited by the reference over time



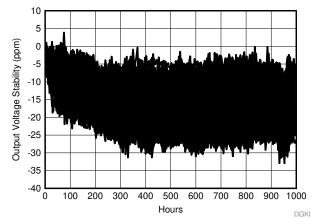


Figure 9-4. Long Term Stability - 1000 hours (V_{REF})
- DBV Package

Figure 9-5. Long Term Stability - 1000 hours (V_{REF}) - DGK Package

9.3 Thermal Hysteresis

Thermal hysteresis is measured with the REF34-Q1 soldered to a PCB, similar to a real-world application. Thermal hysteresis for the device is defined as the change in output voltage after operating the device at 25°C, cycling the device through the specified temperature range, and returning to 25°C. Hysteresis can be expressed by Equation 1:

$$V_{HYST} = \left(\frac{|V_{PRE} - V_{POST}|}{V_{NOM}}\right) \times 10^{6} (ppm)$$
(1)

where

- V_{HYST} = thermal hysteresis (in units of ppm)
- V_{NOM} = the specified output voltage
- V_{PRE} = output voltage measured at 25°C pre-temperature cycling
- V_{POST} = output voltage measured after the device has cycled from 25°C through the specified temperature range of –40°C to +125°C and returns to 25°C.

Typical thermal hysteresis distribution is as shown in Figure 9-6.

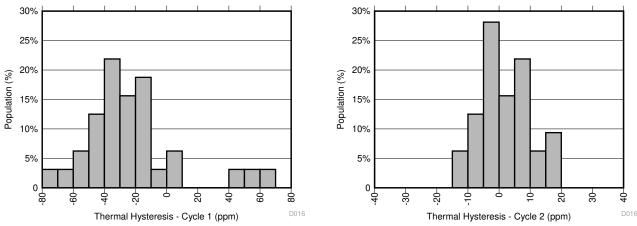
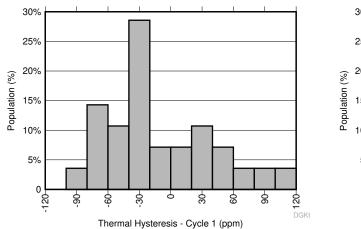


Figure 9-6. Thermal Hysteresis Distribution (V_{REF}) - Figure 9-7. Thermal Hysteresis Distribution (V_{REF}) - DBV Package (Cycle 1) DBV Package (Cycle 2)



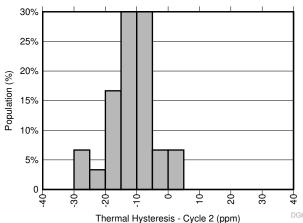


Figure 9-8. Thermal Hysteresis Distribution (V_{REF}) - DGK Package (Cycle 1)

Figure 9-9. Thermal Hysteresis Distribution (V_{REF}) - DGK Package (Cycle 2)

9.4 Power Dissipation

The REF34-Q1 voltage references are capable of source and sink up to 10 mA of load current across the rated input voltage range. However, when used in applications subject to high ambient temperatures, the input voltage and load current must be carefully monitored to ensure that the device does not exceeded its maximum power dissipation rating. The maximum power dissipation of the device can be calculated with Equation 2:

$$T_{J} = T_{A} + P_{D} \times R_{\theta JA} \tag{2}$$

where

- P_D is the device power dissipation
- T_J is the device junction temperature
- · T_A is the ambient temperature
- $R_{\theta JA}$ is the package (junction-to-air) thermal resistance

Because of this relationship, acceptable load current in high temperature conditions may be less than the maximum current-sourcing capability of the device. In no case should the device be operated outside of its maximum power rating because doing so can result in premature failure or permanent damage to the device.



9.5 Noise Performance

Typical 0.1-Hz to 10-Hz voltage noise can be seen in Figure 9-10. Device noise increases with output voltage and operating temperature. Additional filtering can be used to improve output noise levels, although care must be taken to ensure the output impedance does not degrade ac performance. Peak-to-peak noise measurement setup is shown in Figure 9-10.

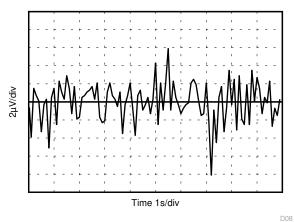


Figure 9-10. 0.1-Hz to 10-Hz Noise (V_{REF})

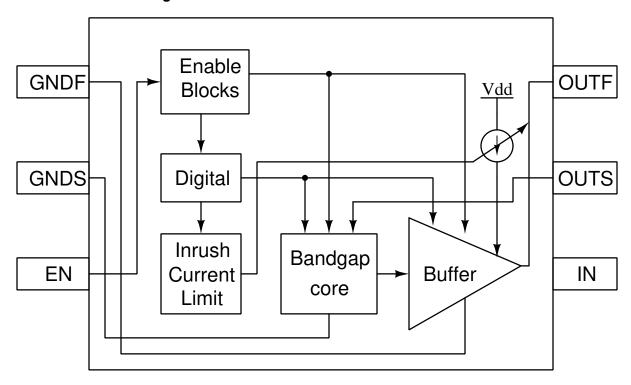


10 Detailed Description

10.1 Overview

The REF34-Q1 devices are a family of low-noise, precision bandgap voltage references that are specifically designed for excellent initial voltage accuracy and drift. The *Section 10.2* is a simplified block diagram of the REF34-Q1 showing basic band-gap topology.

10.2 Functional Block Diagram



10.3 Feature Description

10.3.1 Supply Voltage

The REF34-Q1 family of references features an extremely low dropout voltage. For loaded conditions, a typical dropout voltage versus load is shown on the front page. The REF34-Q1 family features a low quiescent current that is extremely stable over changes in both temperature and supply. The typical room temperature quiescent current is 72 μ A, and the maximum quiescent current over temperature is just 95 μ A. Supply voltages below the specified levels can cause the REF34-Q1 to momentarily draw currents greater than the typical quiescent current. Use a power supply with a fast rising edge and low output impedance to easily prevent this issue.

10.3.2 Low Temperature Drift

The REF34-Q1 devices are designed for minimal drift error, which is defined as the change in output voltage over temperature. The drift is calculated using the box method, as described by Equation 3:

Drift =
$$\left(\frac{V_{REF(MAX)} - V_{REF(MIN)}}{V_{REF} \times Temperature Range}\right) \times 10^{6}$$
(3)

10.3.3 Load Current

The REF34-Q1 family is specified to deliver a current load of ± 10 mA per output. The V_{REF} output of the device are protected from short circuits by limiting the output short-circuit current to 18 mA. The device temperature increases according to Equation 4:

$$T_{J} = T_{A} + P_{D} \times R_{\theta JA} \tag{4}$$

where

- T_J = junction temperature (°C),
- T_A = ambient temperature (°C),
- P_D = power dissipated (W), and
- R_{θ,JA} = junction-to-ambient thermal resistance (°C/W)

The REF34-Q1 maximum junction temperature must not exceed the absolute maximum rating of 150°C.

10.4 Device Functional Modes

10.4.1 EN Pin

When the EN pin of the REF34-Q1 is pulled high, the device is in active mode. The device must be in active mode for normal operation. The REF34-Q1 can be placed in a low-power mode by pulling the ENABLE pin low. When in shutdown mode, the output of the device becomes high impedance and the quiescent current of the device reduces to 2 μ A in shutdown mode. The EN pin must not be pulled higher than VIN supply voltage. See Thermal Information for logic high and logic low voltage levels.

11 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

11.1 Application Information

As the REF34-Q1 devices have many applications and setups, there are many situations that this data sheet can not characterize in detail. Basic applications includes positive/negative voltage reference and data acquisition systems.

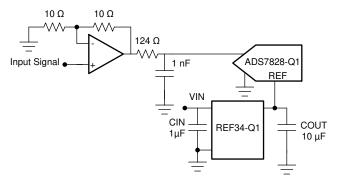
Table 11-1. Typical Applications and Companion ADC/DAC

APPLICATIONS	ADC/DAC/CONTROLLER
ADAS	ADS7828-Q1
HEV/EV	ADS7951-Q1, ADS1120-Q1, ADS1258, BQ76PL455A-Q1

11.2 Typical Applications

11.2.1 Basic Voltage Reference Connection

The circuit shown in Figure 11-1 shows the basic configuration for the REF34-Q1 references. Connect bypass capacitors according to the guidelines in *Section 11.2.1.2.1*.



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Figure 11-1. Basic Reference Connection



11.2.1.1 Design Requirements

A detailed design procedure is based on a design example. For this design example, use the parameters listed in Table 11-2 as the input parameters.

Table 11-2. Design Example Parameters

DESIGN PARAMETER	VALUE		
Input voltage V _{IN}	12 V		
Output voltage V _{OUT}	5 V		
REF3450-Q1 input capacitor	1 μF		
REF3450-Q1 output capacitor	10 μF		

11.2.1.2 Detailed Design Procedure

11.2.1.2.1 Input and Output Capacitors

A $1-\mu F$ to $10-\mu F$ electrolytic or ceramic capacitor can be connected to the input to improve transient response in applications where the supply voltage may fluctuate. Connect an additional $0.1-\mu F$ ceramic capacitor in parallel to reduce high frequency supply noise.

A ceramic capacitor of at least a $0.1~\mu F$ must be connected to the output to improve stability and help filter out high frequency noise. An additional $1-\mu F$ to $10-\mu F$ electrolytic or ceramic capacitor can be added in parallel to improve transient performance in response to sudden changes in load current; however, keep in mind that doing so increases the turnon time of the device.

Best performance and stability is attained with low-ESR, low-inductance ceramic chip-type output capacitors (X5R, X7R, or similar). If using an electrolytic capacitor on the output, place a 0.1-µF ceramic capacitor in parallel to reduce overall ESR on the output.

11.2.1.2.2 4-Wire Kelvin Connections

Current flowing through a PCB trace produces an IR voltage drop, and with longer traces, this drop can reach several millivolts or more, introducing a considerable error into the output voltage of the reference. A 1-inch long, 5-millimeter wide trace of 1-ounce copper has a resistance of approximately $100~\text{m}\Omega$ at room temperature; at a load current of 10~mA, this can introduce a full millivolt of error. In an ideal board layout, the reference must be mounted as close as possible to the load to minimize the length of the output traces, and, therefore, the error introduced by voltage drop. However, in applications where this is not possible or convenient, force and sense connections (sometimes referred to as Kelvin sensing connections) are provided as a means of minimizing the IR drop and improving accuracy.

Kelvin connections work by providing a set of high impedance voltage-sensing lines to the output and ground nodes. Because very little current flows through these connections, the IR drop across their traces is negligible, and the output and ground.

It is always advantageous to use Kelvin connections whenever possible. However, in applications where the IR drop is negligible or an extra set of traces cannot be routed to the load, the force and sense pins for both V_{OUT} and GND can simply be tied together, and the device can be used in the same fashion as a normal 3-terminal reference (as shown in Figure 9-6).

11.2.1.2.3 V_{IN} Slew Rate Considerations

In applications with slow-rising input voltage signals, the reference exhibits overshoot or other transient anomalies that appear on the output. These phenomena also appear during shutdown as the internal circuitry loses power.

To avoid such conditions, ensure that the input voltage wave-form has both a rising and falling slew rate close to 6 V/ms.

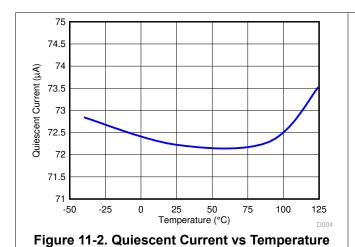


11.2.1.2.4 Shutdown/Enable Feature

The REF34-Q1 references can be switched to a low power shut-down mode when a voltage of 0.5 V or lower is input to the ENABLE pin. Likewise, the reference becomes operational for ENABLE voltages of 1.6 V or higher. During shutdown, the supply current drops to less than $2 \mu A$, useful in applications that are sensitive to power consumption.

If using the shutdown feature, ensure that the ENABLE pin voltage does not fall between 0.5 V and 1.6 V because this causes a large increase in the supply current of the device and may keep the reference from starting up correctly. If not using the shutdown feature, however, the ENABLE pin can simply be tied to the IN pin, and the reference remains operational continuously.

11.2.1.3 Application Curves



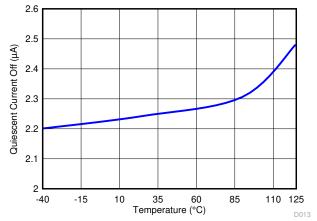


Figure 11-3. Quiescent Current Shutdown Mode

11.2.2 Advanced Driver Assistance Systems (ADAS) Microcontroller Connection

11.2.2.1 Basic Voltage Reference Connection

The circuit shown in Figure 11-4 shows the basic configuration for the REF34-Q1 references.

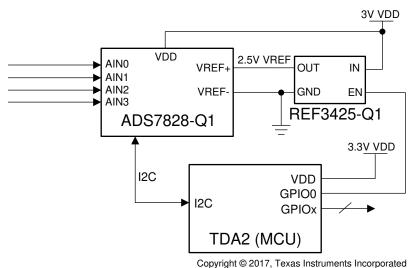


Figure 11-4. ADAS Microcontroller Application

11.2.2.2 Design Requirements

In ADAS applications it is common to use an ADC with a MCU to monitor the voltage rails to the MCU/DSP/FPGAs. In figure Figure 11-4 the automotive TI Jacinto™ TDA2 MCU is using a ADS7828-Q1 to monitor several analog input signals and in ADAS these signals will be the system power rails. It is important to monitor these power rails because tighter rail requirements allow for further system monitoring and optimization. The REF3425-Q1 is used in this application to provide the precise voltage reference signal. In these systems it is not typical to have calibration and such the most precise low power voltage reference is necessary to be able to measure down to 1% accuracy on key power rails.

For this design example, use the parameters listed in Table 11-3 as the input parameters and desired output parameters.

SPECIFICATION	REQUIREMENT						
Input Voltage V _{IN}	3V						
Output Voltage	2.5V						
Voltage Power Rail	1V						
Max Error on Voltage Power Rail	1%						
Temperature Range	-40°C to 125°C						

Table 11-3. Typical Core Voltage Rail Monitoring

11.2.2.3 Detailed Design Procedure

It is important to keep track of the error margin in this system to make sure that the total error of the voltage reference and ADC are less than the maximum 1% error allowed. To calculate the total RSS error of a voltage reference use Equation 5.

$$\mathsf{Error}_{\mathsf{VREF}}\big|_{\mathsf{Total}} = \sqrt{\big(\mathsf{Accuracy}\big)^2 + \big(\mathsf{TempCo}\big)^2 + \big(\mathsf{TempHyst}\big)^2 + \big(\mathsf{LongTerm\ Drift}\big)^2 + \big(\mathsf{1/f\ Noise}\big)^2} \tag{5}$$



With the RSS error of the voltage reference, the ADC error needs also needs to be calculated using the RSS method as seen in Equation 6. Equation 7 can then be used to sum both errors. It is important to make sure that only the applicable voltage reference error in relation to the measured signal is used.

Total Unadjusted Error =
$$\text{Error}_{ADC}|_{\text{Total}}$$

= $\sqrt{\left(\text{Gain Error}\right)^2 + \left(\text{Offset Error}\right)^2 + \left(\text{INL Error}\right)^2 + \left(\text{DNL Error}\right)^2}$ (6)

$$\mathsf{Error}_{\mathsf{VREF}+\mathsf{ADC}}\big|_{\mathsf{Total}} = \sqrt{\left(\mathsf{Error}_{\mathsf{VREF}@\,\mathsf{AIN}}\big|_{\mathsf{Total}}\right)^2 + \left(\mathsf{Error}_{\mathsf{ADC}}\big|_{\mathsf{Total}}\right)^2} \tag{7}$$

11.2.2.4 Enable Feature in ADAS

In ADAS applications it is important to have a low quiescent current when the automotive application does not require the ADAS system to be in use. This creates a need for a low standby power so the battery life is preserved but there is also need for the system to still be readily available to start-up with minimal delays. In such situations the MCU and other systems will go into a standby mode to ensure that the power consumption is lowered to the absolute minimum. The REF3425-Q1 offers an enable pin that can be controlled by the MCU to activate shutdown mode with causes the REF3425-Q1 to go into stand by and consume 3 μ A (maximum) and allow for a longer battery life.

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12 Power Supply Recommendations

The REF34-Q1 family of references feature an extremely low-dropout voltage. These references can be operated with a supply of only 50 mV above the output voltage. TI recommends a supply bypass capacitor ranging between 0.1 μ F to 10 μ F.

13 Layout

13.1 Layout Guidelines

Figure 13-1 illustrates an example of a PCB layout for a data acquisition system using the REF34-Q1. Some key considerations are:

- Connect low-ESR, 0.1-μF ceramic bypass capacitors at V_{IN}, V_{REF} of the REF34-Q1.
- Decouple other active devices in the system per the device specifications.
- Using a solid ground plane helps distribute heat and reduces electromagnetic interference (EMI) noise pickup.
- Place the external components as close to the device as possible. This configuration prevents parasitic errors (such as the Seebeck effect) from occurring.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible, and only make perpendicular crossings when absolutely necessary.

13.2 Layout Example

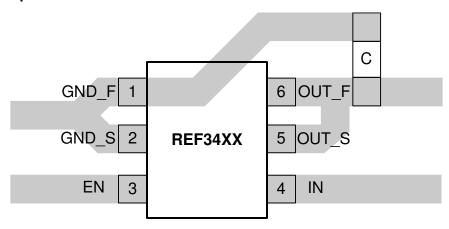


Figure 13-1. Layout Example (REF34xx-Q1 DBV Package)

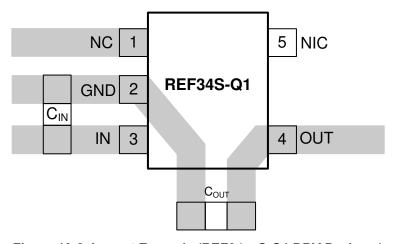


Figure 13-2. Layout Example (REF34xxS-Q1 DBV Package)



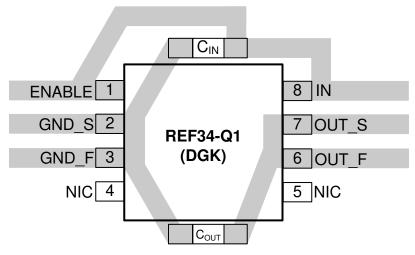


Figure 13-3. Layout Example (REF34xx-Q1 DGK Package)

14 Device and Documentation Support

14.1 Documentation Support

14.1.1 Related Documentation

For related documentation see the following:

- INA21x Voltage Output, Low- or High-Side Measurement, Bidirectional, Zero-Drift Series, Current-Shunt Monitors
- Low-Drift Bidirectional Single-Supply Low-Side Current Sensing Reference Design

14.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

14.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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14.4 Trademarks

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TI E2E[™] is a trademark of Texas Instruments.

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14.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

14.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

15 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
REF3425QDBVRQ1	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1OLC
REF3425QDBVRQ1.B	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1OLC
REF3425QDGKRQ1	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2E93
REF3425QDGKRQ1.B	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2E93
REF3425SQDBVRQ1	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2D6C
REF3425SQDBVRQ1.B	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2D6C
REF3430QDBVRQ1	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1OMC
REF3430QDBVRQ1.B	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1OMC
REF3430QDGKRQ1	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2FW3
REF3430QDGKRQ1.B	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2FW3
REF3430SQDBVRQ1	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2D7C
REF3430SQDBVRQ1.B	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2D7C
REF3433QDBVRQ1	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1ONC
REF3433QDBVRQ1.B	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	10NC
REF3433QDGKRQ1	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2FV3
REF3433QDGKRQ1.B	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2FV3
REF3433SQDBVRQ1	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2D8C
REF3433SQDBVRQ1.B	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2D8C
REF3440QDBVRQ1	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	100C
REF3440QDBVRQ1.B	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	100C
REF3440QDGKRQ1	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2FQ3
REF3440QDGKRQ1.B	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2FQ3
REF3440SQDBVRQ1	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2D9C
REF3440SQDBVRQ1.B	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2D9C
REF3450QDBVRQ1	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	10PC
REF3450QDBVRQ1.B	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	10PC
REF3450QDGKRQ1	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2FX3
REF3450QDGKRQ1.B	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	2FX3
REF3450SQDBVRQ1	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2DAC



PACKAGE OPTION ADDENDUM

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Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
REF3450SQDBVRQ1.B	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2DAC

⁽¹⁾ Status: For more details on status, see our product life cycle.

- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.



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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
REF3425QDBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
REF3425QDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
REF3425SQDBVRQ1	SOT-23	DBV	5	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
REF3430QDBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
REF3430QDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
REF3430SQDBVRQ1	SOT-23	DBV	5	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
REF3433QDBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
REF3433QDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
REF3433SQDBVRQ1	SOT-23	DBV	5	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
REF3440QDBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
REF3440QDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
REF3440SQDBVRQ1	SOT-23	DBV	5	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
REF3450QDBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
REF3450QDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
REF3450SQDBVRQ1	SOT-23	DBV	5	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3



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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
REF3425QDBVRQ1	SOT-23	DBV	6	3000	213.0	191.0	35.0
REF3425QDGKRQ1	VSSOP	DGK	8	2500	366.0	364.0	50.0
REF3425SQDBVRQ1	SOT-23	DBV	5	3000	213.0	191.0	35.0
REF3430QDBVRQ1	SOT-23	DBV	6	3000	213.0	191.0	35.0
REF3430QDGKRQ1	VSSOP	DGK	8	2500	366.0	364.0	50.0
REF3430SQDBVRQ1	SOT-23	DBV	5	3000	213.0	191.0	35.0
REF3433QDBVRQ1	SOT-23	DBV	6	3000	213.0	191.0	35.0
REF3433QDGKRQ1	VSSOP	DGK	8	2500	366.0	364.0	50.0
REF3433SQDBVRQ1	SOT-23	DBV	5	3000	213.0	191.0	35.0
REF3440QDBVRQ1	SOT-23	DBV	6	3000	213.0	191.0	35.0
REF3440QDGKRQ1	VSSOP	DGK	8	2500	366.0	364.0	50.0
REF3440SQDBVRQ1	SOT-23	DBV	5	3000	213.0	191.0	35.0
REF3450QDBVRQ1	SOT-23	DBV	6	3000	213.0	191.0	35.0
REF3450QDGKRQ1	VSSOP	DGK	8	2500	366.0	364.0	50.0
REF3450SQDBVRQ1	SOT-23	DBV	5	3000	213.0	191.0	35.0





NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.

- 4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
- 5. Refernce JEDEC MO-178.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
 3. Reference JEDEC MO-178.

- 4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
- 5. Support pin may differ or may not be present.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE PACKAGE



NOTES:

PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-187.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.
- 9. Size of metal pad may vary due to creepage requirement.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 12. Board assembly site may have different recommendations for stencil design.



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Last updated 10/2025